BIBLIOGRAPHIE FREDERIC WROBEL

A semi-empirical approach for heavy ion SEU cross section calculations

F Wrobel, G Hubert… - IEEE transactions on nuclear science, 2006 - cat.inist.fr
The main goal of this paper is to propose an approach to calculate heavy ion SEU cross sections. The starting point is the diffusion model theory, which allows the charges diffusion but does not account for electrical field in the device. This electrical field is not necessary **...**
Cité 3 fois - Autres articles - Les 3 versions

Natural radioactivity consideration for high-κ dielectrics and metal gates choice in nanoelectronic devices

M Gedion, F Wrobel… - Journal of Physics D: Applied …, 2010 - iopscience.iop.org
... high-κ dielectrics and metal gates choice in nanoelectronic devices Michael Gedion, **Frédéric Wrobel** and Frédéric Saigné Institut d'Electronique du Sud (IES), Université de Montpellier II, UMR-CNRS 5214, 34095 Montpellier, France E-mail: michael.gedion@ies.univ-montp2.fr **...**
Autres articles - Les 5 versions

Measurement and calculation of charge deposition in a silicon diode irradiated by 30 MeV protons

S Rocheman, F Wrobel, F Saigne… - Journal of Applied …, 2009 - ieeexplore.ieee.org
The aim of this work is to validate the results of the MC-RED nuclear physics code used to determine the deposited energy in a silicon volume taking into account the probabilistic approach of the physical phenomenon. A silicon diode has been irradiated by a quasimonoenergetic **...**
Les 5 versions

Neutron Induced Energy Deposition in a Silicon Diode

S Rocheman, F Wrobel, JR Vaille… - Nuclear Science, …, 2009 - ieeexplore.ieee.org
Abstract—Simulation of energy deposition in silicon by nuclear reactions is a crucial point for single event prediction tool devel- opment. In order to compare with the simulation of nuclear reac- tions, a silicon diode is irradiated by a 30 MeV and 63 MeV neutron beam and the **...**
Autres articles - Les 2 versions

Neutron detection through an SRAM-based test bench

[PDF] à partir de archives-ouvertes.frL Dilillo, F Wrobel, JM Galliere… - Advances in sensors …, 2009 - ieeexplore.ieee.org
1 Laboratoire d'Informatique, de Robotique et de Microélectronique de Montpellier – LIRMM Université de Montpellier II / CNRS 161, rue Ada – 34392 Montpellier Cedex 5, France Email: <lastname>@lirmm.fr URL: http://www.lirmm.fr/~w3mic **...** 2 Institut d'Electronique **...**
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He and Ne ages of large presolar silicon carbide grains: Solving the recoil problem

[PDF] à partir de arxiv.orgU Ott, PR Heck, F Gyngard, R Wieler… - Publications of the …, 2009 - CSIRO
Page 1. CSIRO PUBLISHING www.publish.csiro.au/journals/pasa Publications of the Astronomical Society of Australia, 2009, 26, 297–302 He and Ne Ages of Large Presolar Silicon Carbide Grains: Solving the Recoil Problem **...**
Autres articles - Les 11 versions

Manufacturers to end-users tools for radiations induced reliability issues in electronic devices

F Wrobel - Test Workshop (LATW), 2010 11th Latin American, 2010 - ieeexplore.ieee.org
Abstract— Natural radiations induced failures in microelec- tronics has first been a real concern for space and avionic com- munities. Due to device integration this is now an issue for all commercial applications even at ground level. As an example, single event transients and soft errors **...**

MC-ORACLE: A tool for predicting Soft Error Rate

F Wrobel… - Computer Physics Communications, 2010 - Elsevier
Natural radiation is known to be a source of microelectronics failure. For instance, neutrons, protons, heavy ions, and alpha particles have all been implicated in the occurrence of soft errors in memory devices. To predict the reliability of electronics devices we developed a tool **...**